

STANDARD

I.S. EN 60749-24:2004

ICS 31.080

National Standards Authority of Ireland Dublin 9 Ireland

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SEMICONDUCTOR DEVICES - MECHANICAL

AND CLIMATIC TEST METHODS PART 24:

ACCELERATED MOISTURE RESISTANCE -

UNBIASED HAST (IEC 60749-24:2004)

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EUROPEAN STANDARD NORME EUROPÉENNE

EN 60749-24

EUROPÄISCHE NORM

April 2004

ICS 31.080

English version

Semiconductor devices – Mechanical and climatic test methods Part 24: Accelerated moisture resistance – Unbiased HAST

(IEC 60749-24:2004)

Dispositifs à semiconducteurs – Méthodes d'essais mécaniques et climatiques Partie 24: Résistance à l'humidité accélérée – HAST sans polarisation (CEI 60749-24:2004)

Halbleiterbauelemente –
Mechanische und klimatische
Prüfverfahren
Teil 24: Beschleunigte Verfahren für
Feuchtebeständigkeit Hochbeschleunigte Wirkung (HAST)
ohne elektrische Beanspruchung
(IEC 60749-24:2004)

This European Standard was approved by CENELEC on 2004-04-01. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the Central Secretariat or to any CENELEC member.

This European Standard exists in three official versions (English, French, German). A version in any other language made by translation under the responsibility of a CENELEC member into its own language and notified to the Central Secretariat has the same status as the official versions.

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CENELEC

European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

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Foreword

The text of document 47/1736/FDIS, future edition 1 of IEC 60749-24, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60749-24 on 2004-04-01.

The following dates were fixed:

 latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement

(dop) 2005-01-01

 latest date by which the national standards conflicting with the EN have to be withdrawn

(dow) 2007-04-01

Annex ZA has been added by CENELEC.

Endorsement notice

The text of the International Standard IEC 60749-24:2004 was approved by CENELEC as a European Standard without any modification.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following referenced documents are indispensable for the application of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE Where an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	EN/HD	<u>Year</u>
IEC 60749-33	- 1)	Semiconductor devices - Mechanical and climatic test methods Part 33: Accelerated moisture resistance - Unbiased autoclave	EN 60749-33	2004 2)
IEC 60749-5	- 1)	Part 5: Steady-state temperature humidity bias life test	EN 60749-5	2003 2)

¹⁾ Undated reference.

²⁾ Valid edition at date of issue.

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